S	earc	n	Note	es

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/796,783	INOUE ET AL.	
Examiner	Art Unit	
Mike Qi	2871	

	SEAR	CHED	
Class	Subclass	Date	Examiner
349	129,130 92-94,88	1/5/2006	ZQQ
345	80	1/5/2006	ZQQ
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INT	ERFERENC	ENCE SEARCHED		
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SEARCH NO (INCLUDING SEARCH		)
	DATE	EXMR
East search US-PGPUB;USPAT;USOCR; EPO;JPO;DERWENT;IBM_TDB; (see search history printout)	1/5/2006	zqq